

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10692176	SIEPMANN, JAMES P.
<b>Examiner</b>	<b>Art Unit</b>	
HANH PHAN	2613	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
398	154, 155, 158, 159, 161, 102, 53, 45, 192, 175, 176, 140, 214, 183, 141	07/14/2011	HP
385	24, 14, 15, 27, 16, 17, 18	07/14/2011	HP
372	25, 30, 32, 38.02, 38.07, 69, 22, 29	07/14/2011	HP
UPDATE SEARCH		07/14/2011	HP

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST SEARCH SEE ATTACHED PRINTOUT IN THE FILE	07/14/2011	HP
IEEE SEARCH	07/14/2011	HP
JPO SEARCH	07/14/2011	HP
PGPUB TEXT SEARCH SEE INTERFERENCE SEARCH PRINTOUT	07/14/2011	HP

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
398	154, 155, 158, 159, 161, 102, 53, 45, 192, 175, 176, 140, 214, 183, 141	07/14/2011	HP
385	24, 14, 15, 27, 16, 17, 18	07/14/2011	HP
372	25, 30, 32, 38.02, 38.07, 69, 22, 29	07/14/2011	HP

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